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INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ/T 2658.7-2015

Replacing SJ/T 2658.7-1986

Measuring method for semiconductor infrared-emitting diode. Part 7: Radiant flux

半导体红外发射二极管测量方法 第7部分：辐射通量

(English Translation)

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What this standard covers

This standard specifies the measurement principle, measurement procedure and specified conditions for the radiation flux of semiconductor infrared emitting diodes (hereinafter referred to as devices). This standard applies to semiconductor infrared emitting diodes.

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